

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/764,449	OJIMA ET AL.	
Examiner Justin P. Misleh		Art Unit 2612	Page 1 of 1	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,243,136 B1	06-2001	Sasaki, Saburo	348/362
*	B	US-2003/0030740 A1	02-2003	Tsujino, Kazuhiro	348/333.01
*	C	US-2003/0086005 A1	05-2003	Nakamura, Hideo	348/223.1
*	D	US-2003/0030737 A1	02-2003	Yanai, Toshikazu	348/296
*	E	US-2003/0098917 A1	05-2003	Oda, Kazuya	348/272
*	F	US-2003/0128279 A1	07-2003	Suzuki, Nobuo	348/221.1
*	G	US-6,157,406 A	12-2000	Iura et al.	348/220.1
*	H	US-6,657,671 B1	12-2003	Sasaki, Saburo	348/367
*	I	US-6,947,089 B1	09-2005	Hori, Masashi	348/312
*	J	US-6,888,570 B1	05-2005	Yoshida, Hideaki	348/296
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 04281684 A	10-1992	Japan	OYOSHI, MASAHIKO	H04N 05/335
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.